

# SEMiX302GB126HDs



SEMiX<sup>®</sup> 2s

## Trench IGBT Modules

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#### Features

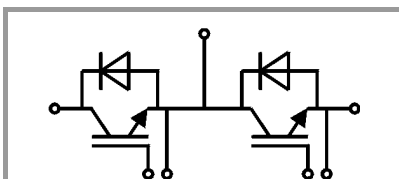
- Homogeneous Si
- Trench = Trenchgate technology
- $V_{CE(sat)}$  with positive temperature coefficient
- High short circuit capability
- UL recognised file no. E63532

#### Typical Applications\*

- AC inverter drives
- UPS
- Electronic Welding

#### Remarks

- Case temperatur limited to  $T_C=125^\circ\text{C}$  max.
- Not for new design



GB

#### Absolute Maximum Ratings

Symbol	Conditions	Values	Unit	
<b>IGBT</b>				
$V_{CES}$	$T_j = 25^\circ\text{C}$	1200	V	
$I_C$	$T_j = 150^\circ\text{C}$	$T_c = 25^\circ\text{C}$	311	A
		$T_c = 80^\circ\text{C}$	218	A
$I_{Cnom}$		200	A	
$I_{CRM}$	$I_{CRM} = 2 \times I_{Cnom}$	400	A	
$V_{GES}$		-20 ... 20	V	
$t_{psc}$	$T_j = 125^\circ\text{C}$	$V_{CC} = 600\text{ V}$ $V_{GE} \leq 20\text{ V}$ $V_{CES} \leq 1200\text{ V}$	10	$\mu\text{s}$
			-40 ... 150	$^\circ\text{C}$
$T_j$				
<b>Inverse diode</b>				
$I_F$	$T_j = 150^\circ\text{C}$	$T_c = 25^\circ\text{C}$	292	A
		$T_c = 80^\circ\text{C}$	202	A
$I_{Fnom}$		200	A	
$I_{FRM}$	$I_{FRM} = 2 \times I_{Fnom}$	400	A	
$I_{FSM}$	$t_p = 10\text{ ms, sin } 180^\circ, T_j = 25^\circ\text{C}$	1300	A	
$T_j$		-40 ... 150	$^\circ\text{C}$	
<b>Module</b>				
$I_{t(RMS)}$	$T_{terminal} = 80^\circ\text{C}$	600	A	
$T_{stg}$		-40 ... 125	$^\circ\text{C}$	
$V_{isol}$	AC sinus 50Hz, $t = 1\text{ min}$	4000	V	

#### Characteristics

Symbol	Conditions	min.	typ.	max.	Unit
<b>IGBT</b>					
$V_{CE(sat)}$	$I_C = 200\text{ A}$ $V_{GE} = 15\text{ V}$ chipllevel	$T_j = 25^\circ\text{C}$	1.7	2.1	V
		$T_j = 125^\circ\text{C}$	2.0	2.45	V
$V_{CE0}$		$T_j = 25^\circ\text{C}$	1	1.2	V
		$T_j = 125^\circ\text{C}$	0.9	1.1	V
$r_{CE}$	$V_{GE} = 15\text{ V}$	$T_j = 25^\circ\text{C}$	3.5	4.5	$\text{m}\Omega$
		$T_j = 125^\circ\text{C}$	5.5	6.8	$\text{m}\Omega$
$V_{GE(th)}$	$V_{GE} = V_{CE}, I_C = 8\text{ mA}$	5	5.8	6.5	V
$I_{CES}$	$V_{GE} = 0\text{ V}$ $V_{CE} = 1200\text{ V}$	$T_j = 25^\circ\text{C}$	0.1	0.3	mA
		$T_j = 125^\circ\text{C}$			mA
$C_{ies}$	$V_{CE} = 25\text{ V}$		14.4		nF
$C_{oes}$	$V_{GE} = 0\text{ V}$		0.75		nF
$C_{res}$			0.65		nF
$Q_G$	$V_{GE} = -8\text{ V...} + 15\text{ V}$		1600		nC
$R_{Gint}$	$T_j = 25^\circ\text{C}$		3.75		$\Omega$
$t_{d(on)}$	$V_{CC} = 600\text{ V}$ $I_C = 200\text{ A}$		320		ns
$t_r$	$V_{GE} = \pm 15\text{ V}$		50		ns
$E_{on}$	$R_{G on} = 2.8\ \Omega$		30		mJ
$t_{d(off)}$	$R_{G off} = 2.8\ \Omega$		600		ns
$t_f$			100		ns
$E_{off}$			26		mJ
$R_{th(j-c)}$	per IGBT			0.12	K/W

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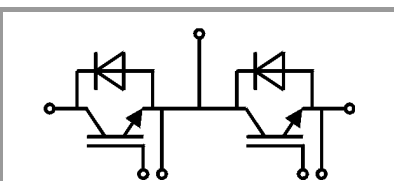
#### Typical Applications\*

- AC inverter drives
- UPS
- Electronic Welding

#### Remarks

- Case temperatur limited to  $T_C=125^\circ\text{C}$  max.
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Characteristics						
Symbol	Conditions		min.	typ.	max.	Unit
<b>Inverse diode</b>						
$V_F = V_{EC}$	$I_F = 200\text{ A}$	$T_j = 25^\circ\text{C}$		1.6	1.80	V
	$V_{GE} = 0\text{ V}$	$T_j = 125^\circ\text{C}$		1.6	1.8	V
	chip					
$V_{F0}$		$T_j = 25^\circ\text{C}$	0.9	1	1.1	V
		$T_j = 125^\circ\text{C}$	0.7	0.8	0.9	V
$r_F$		$T_j = 25^\circ\text{C}$	2.5	3.0	3.5	m $\Omega$
		$T_j = 125^\circ\text{C}$	3.5	4.0	4.5	m $\Omega$
$I_{RRM}$	$I_F = 200\text{ A}$	$T_j = 125^\circ\text{C}$		290		A
$Q_{rr}$	$di/dt_{off} = 5900\text{ A}/\mu\text{s}$	$T_j = 125^\circ\text{C}$		55		$\mu\text{C}$
$E_{rr}$	$V_{GE} = -15\text{ V}$	$T_j = 125^\circ\text{C}$		22.5		mJ
	$V_{CC} = 600\text{ V}$					
$R_{th(j-c)}$	per diode				0.19	K/W
<b>Module</b>						
$L_{CE}$				18		nH
$R_{CC+EE}$	res., terminal-chip	$T_C = 25^\circ\text{C}$		0.7		m $\Omega$
		$T_C = 125^\circ\text{C}$		1		m $\Omega$
$R_{th(c-s)}$	per module			0.045		K/W
$M_s$	to heat sink (M5)		3		5	Nm
$M_t$	to terminals (M6)		2.5		5	Nm
w					250	g
<b>Temperatur Sensor</b>						
$R_{100}$	$T_c=100^\circ\text{C}$ ( $R_{25}=5\text{ k}\Omega$ )			$493 \pm 5\%$		$\Omega$
$B_{100/125}$	$R_{(T)}=R_{100}\exp[B_{100/125}(1/T-1/T_{100})]$ ; T[K];			$3550 \pm 2\%$		K



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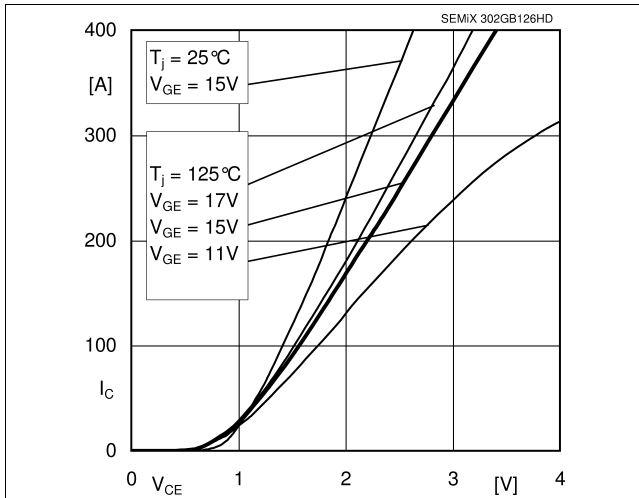


Fig. 1: Typ. output characteristic, inclusive  $R_{CC} + E_E$

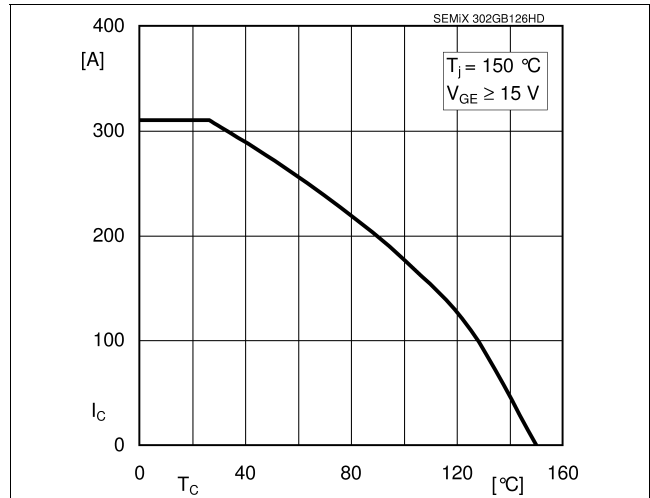


Fig. 2: Rated current vs. temperature  $I_c = f(T_C)$

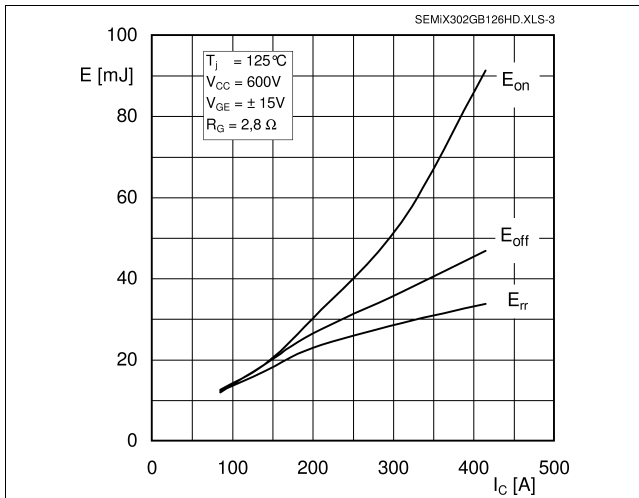


Fig. 3: Typ. turn-on /-off energy =  $f(I_c)$

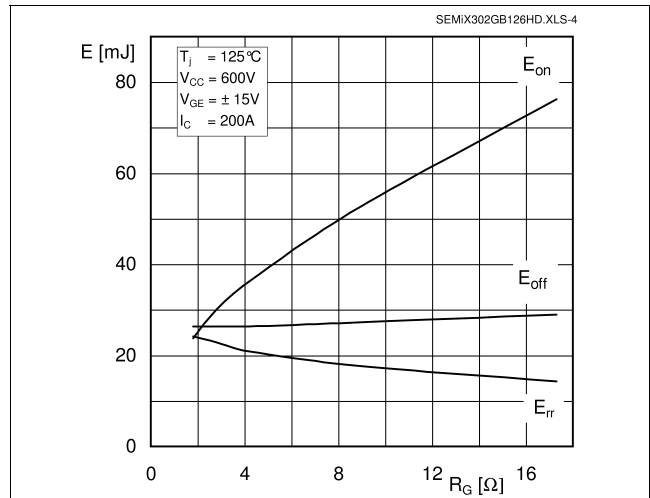


Fig. 4: Typ. turn-on /-off energy =  $f(R_G)$

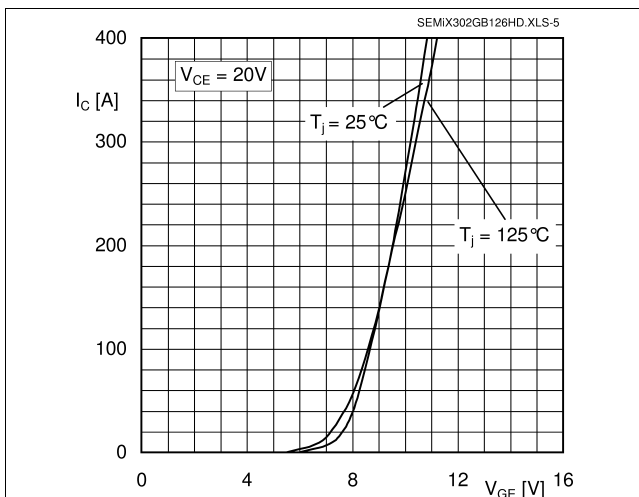


Fig. 5: Typ. transfer characteristic

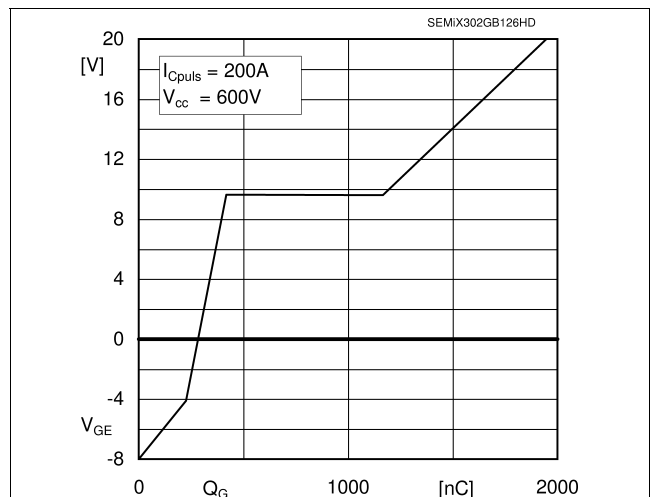


Fig. 6: Typ. gate charge characteristic

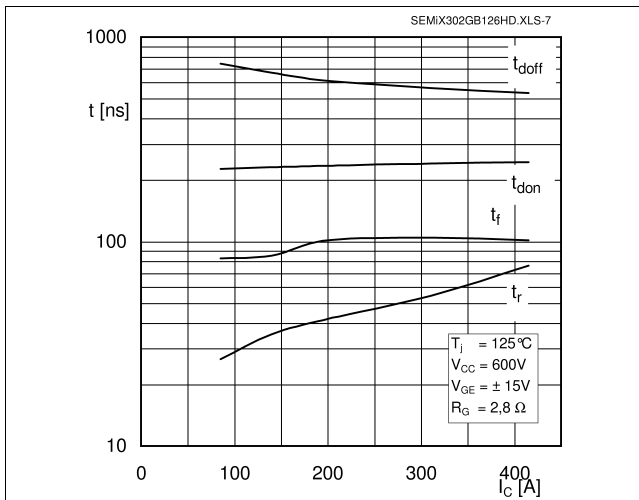


Fig. 7: Typ. switching times vs.  $I_c$

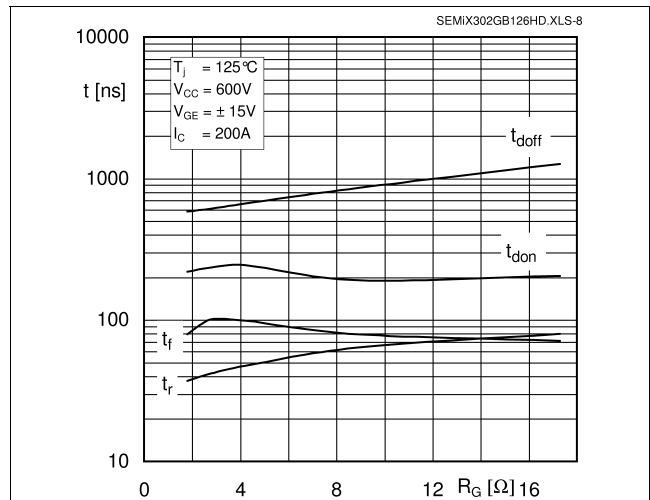


Fig. 8: Typ. switching times vs. gate resistor  $R_G$

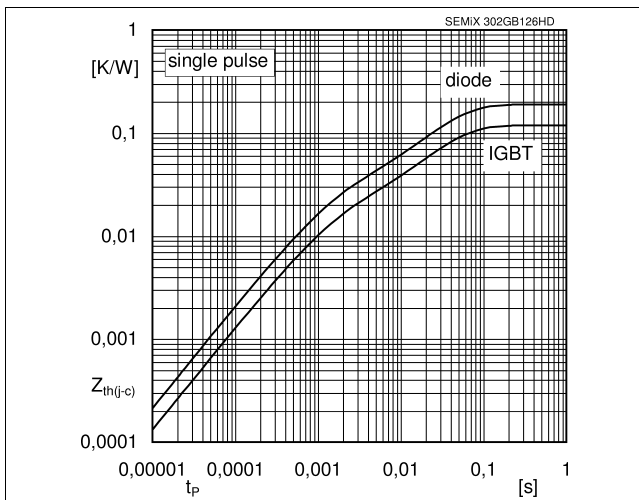


Fig. 9: Typ. transient thermal impedance

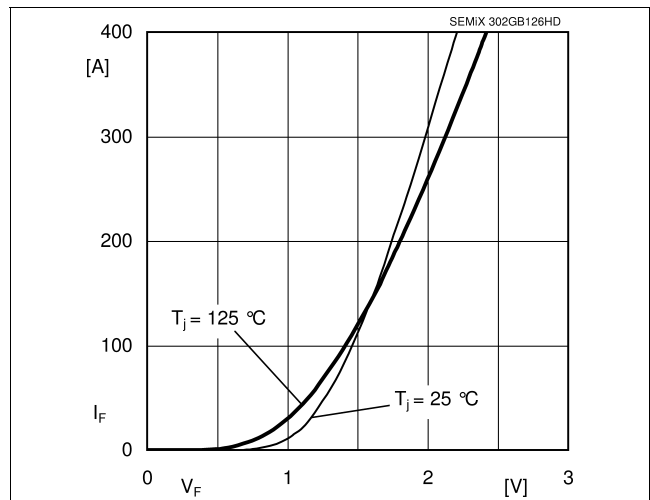


Fig. 10: Typ. CAL diode forward charact., incl.  $R_{CC+EE}$

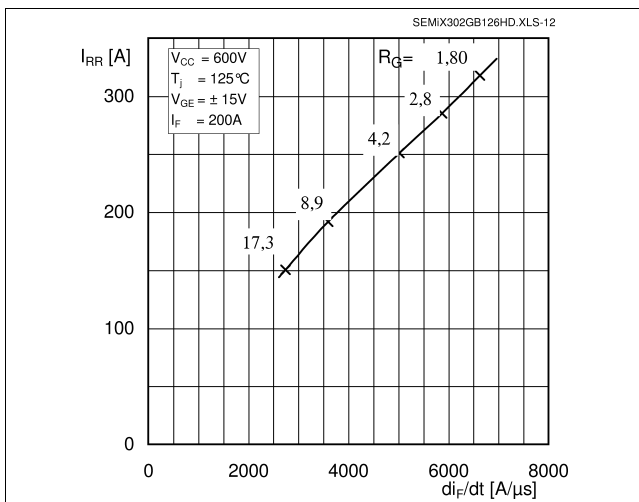


Fig. 11: Typ. CAL diode peak reverse recovery current

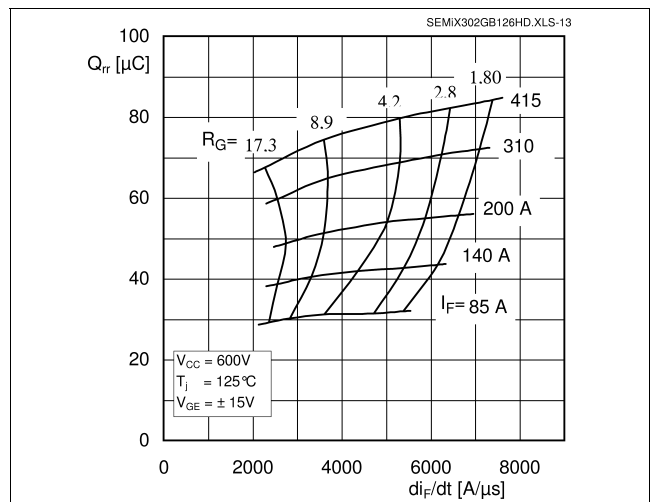


Fig. 12: Typ. CAL diode recovery charge

